Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination TAKAHASHI ET AL	
10/645,249		
Examiner	Art Unit	
Justin Krause	3682	

Justin Krause

	SEAR	CHED	
Class	Subclass	Date	Examiner
Update	Above	11/8/2007	JMK

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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